



National Standards Authority of Ireland

IRISH STANDARD

**I.S. EN 60749-8:2003**

ICS 31.080.01

**SEMICONDUCTOR DEVICES -  
MECHANICAL AND CLIMATIC TEST  
METHODS**

**PART 8: SEALING**

**(IEC 60749-8:2002 + CORRIGENDUM 2003)**

National Standards  
Authority of Ireland  
Dublin 9  
Ireland

Tel: (01) 807 3800  
Tel: (01) 807 3838

*This Irish Standard was  
published under the  
authority of the National  
Standards Authority of  
Ireland  
and comes into effect on:  
August 22, 2003*

**NO COPYING WITHOUT NSAI  
PERMISSION EXCEPT AS  
PERMITTED BY COPYRIGHT  
LAW**

© NSAI 2003

**Price Code M**

Údarás um Chaighdeán Náisiúnta na hÉireann



**CEI 60749-8**  
(Première édition – 2002)

**Dispositifs à semiconducteurs –  
Méthodes d'essais mécaniques et climatiques –**

**Partie 8: Etanchéité**

**IEC 60749-8**  
(First edition – 2002)

**Semiconductor devices –  
Mechanical and climatic test methods –**

**Part 8: Sealing**

## **CORRIGENDUM 1**

Page 28

9.4 Critères de défaillance

*Première phrase*

*Au lieu de:*

Un dispositif doit être rejeté s'il gagne 1,0 mg au moins et s'il a un volume interne  $\geq 0,01 \text{ cm}^3$  et 2,0 mg au moins si le volume est  $> 0,01 \text{ cm}^3$ .

*lire:*

Un dispositif doit être rejeté s'il gagne 1,0 mg au moins et s'il a un volume interne  $\leq 0,01 \text{ cm}^3$  et 2,0 mg au moins si le volume est  $> 0,01 \text{ cm}^3$ .

**CE CORRIGENDUM EST AUSSI  
VALABLE POUR:**

CEI 60749  
Dispositifs à semiconducteurs –  
Essais mécaniques et climatiques  
Amendement 2 (2001), page 60 et  
Edition 2.2 (2002), page 132, sous  
5.7.4 Critères de défaillance

Page 29

9.4 Failure criteria

*First sentence*

*Instead of:*

A device shall be rejected if it gains 1,0 mg or more and has an internal volume of  $\geq 0,01 \text{ cm}^3$  and 2,0 mg or more if the volume is  $> 0,01 \text{ cm}^3$ .

*read:*

A device shall be rejected if it gains 1,0 mg or more and has an internal volume of  $\leq 0,01 \text{ cm}^3$  and 2,0 mg or more if the volume is  $> 0,01 \text{ cm}^3$ .

**THIS CORRIGENDUM IS ALSO VALID  
FOR:**

IEC 60749  
Semiconductor devices –  
Mechanical and climatic test methods  
Amendment 2 (2001), page 61 and  
Edition 2.2 (2002), page 133, under  
5.7.4 Failure criteria

EUROPEAN STANDARD

**EN 60749-8**

NORME EUROPÉENNE

EUROPÄISCHE NORM

June 2003

ICS 31.080.01

English version

**Semiconductor devices -  
Mechanical and climatic test methods  
Part 8: Sealing  
(IEC 60749-8:2002 + corrigendum 2003)**

Dispositifs à semiconducteurs -  
Méthodes d'essais mécaniques  
et climatiques  
Partie 8: Etanchéité  
(CEI 60749-8:2002 + corrigendum 2003)

Halbleiterbauelemente -  
Mechanische und klimatische Prüfverfahren  
Teil 8: Dichtheit  
(IEC 60749-8:2002 + Corrigendum 2003)

This European Standard was approved by CENELEC on 2002-09-24. CENELEC members are bound to comply with the CEN/CENELEC Internal Regulations which stipulate the conditions for giving this European Standard the status of a national standard without any alteration.

Up-to-date lists and bibliographical references concerning such national standards may be obtained on application to the Central Secretariat or to any CENELEC member.

This European Standard exists in three official versions (English, French, German). A version in any other language made by translation under the responsibility of a CENELEC member into its own language and notified to the Central Secretariat has the same status as the official versions.

CENELEC members are the national electrotechnical committees of Austria, Belgium, Czech Republic, Denmark, Finland, France, Germany, Greece, Hungary, Iceland, Ireland, Italy, Luxembourg, Malta, Netherlands, Norway, Portugal, Slovakia, Spain, Sweden, Switzerland and United Kingdom.

**CENELEC**

European Committee for Electrotechnical Standardization  
Comité Européen de Normalisation Electrotechnique  
Europäisches Komitee für Elektrotechnische Normung

**Central Secretariat: rue de Stassart 35, B - 1050 Brussels**

## Foreword

The text of the International Standard IEC 60749-8:2002 was approved by CENELEC as EN 60749-8 on 2002-09-24.

The text of this International Standard was reproduced from IEC 60749:1996, chapter 3, clause 5 without change. Therefore, it has not been submitted to vote a second time and is still based on document 47/1574/FDIS.

The following dates were fixed:

- latest date by which the EN has to be implemented  
at national level by publication of an identical  
national standard or by endorsement (dop) 2004-01-01
- latest date by which the national standards conflicting  
with the EN have to be withdrawn (dow) 2005-10-01

Each test method governed by this standard and which is part of the series is a stand-alone document, numbered EN 60749-2, EN 60749-3, etc. The numbering of these test methods is sequential, and there is no relationship between the number and the test method (i.e. no grouping of test methods). The list of these tests will be available in the CENELEC internet site and in the catalogue.

Updating of any of the individual test methods is independent of any other part.

Annexes designated "normative" are part of the body of the standard.  
In this standard, annex ZA is normative.  
Annex ZA has been added by CENELEC.

---

## Endorsement notice

The text of the International Standard IEC 60749-8:2002 and its corrigendum April 2003 was approved by CENELEC as a European Standard without any modification.

---

## **Annex ZA** (normative)

### **Normative references to international publications with their corresponding European publications**

This European Standard incorporates by dated or undated reference, provisions from other publications. These normative references are cited at the appropriate places in the text and the publications are listed hereafter. For dated references, subsequent amendments to or revisions of any of these publications apply to this European Standard only when incorporated in it by amendment or revision. For undated references the latest edition of the publication referred to applies (including amendments).

NOTE When an international publication has been modified by common modifications, indicated by (mod), the relevant EN/HD applies.

<u>Publication</u>	<u>Year</u>	<u>Title</u>	<u>EN/HD</u>	<u>Year</u>
IEC 60068-2-17	1994	Environmental testing Part 2: Tests - Test Q: Sealing	EN 60068-2-17	1994

This is a free preview. Purchase the entire publication at the link below:

[Product Page](#)

- 
- Looking for additional Standards? Visit Intertek Inform Infostore
  - Learn about LexConnect, All Jurisdictions, Standards referenced in Australian legislation
-